

EE534P-Device Simulation Lab

Problem Sheet 5

Numerical solution of Poisson's equation with Maxwell-Boltzmann distribution of carrier density:

- a. Assuming electrons as the only type of carriers and an undoped semiconductor, write the appropriate form of Poisson's equation for electrostatics (assume that the current is zero, and Maxwell-Boltzmann statistics for carriers).
- b. Discretize the above equation such that finite difference method could be used to solve the same.
- c. List out the general form for Jacobian for the above set of equations.
- d. Consider a semiconductor (say, Silicon) of thickness $200\mu\text{m}$. Assume that one end (A) is held at 100mV while the other (B) is held at zero potential. Using a-c given above, solve for this system using Newton's method. Use a linearly varying potential profile as the initial guess. Plot the potential and carrier density profiles.
- e. Repeat (d) for applied biases like 200mV , 400mV , and 600mV . Analyse your solutions.
- f. Assume that SiO_2 of thickness 20nm is deposited at the end A and the potential is applied across the SiO_2 and the Semiconductor. Modify your code in (d) and find the carrier density profiles inside the semiconductor for an applied bias of 1V . Comment on your results.